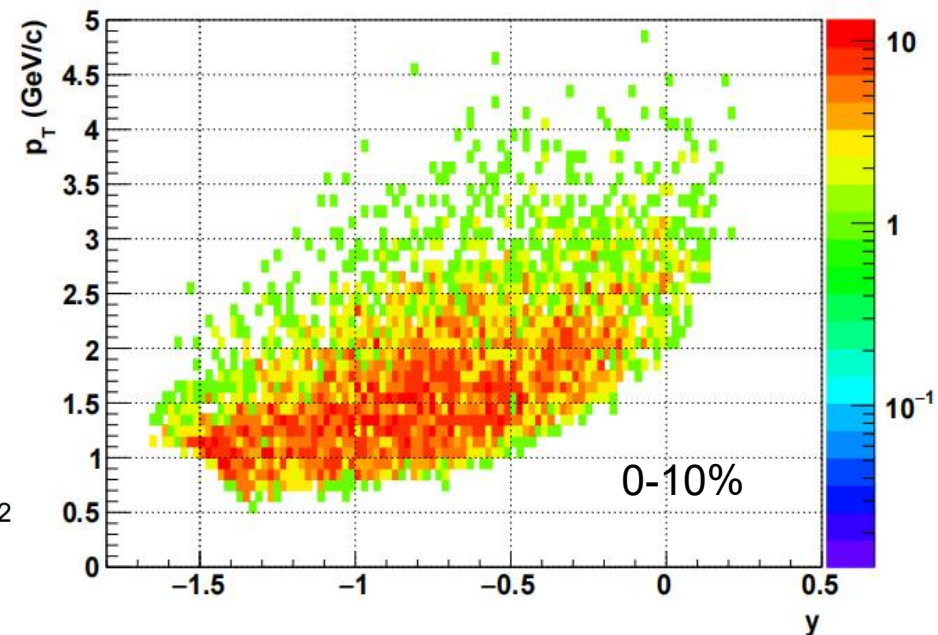
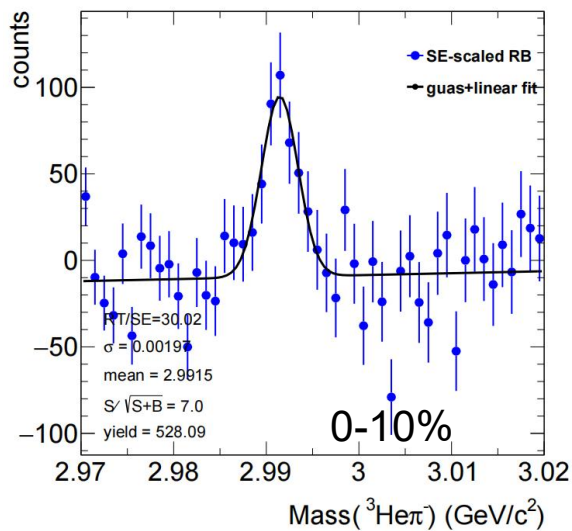
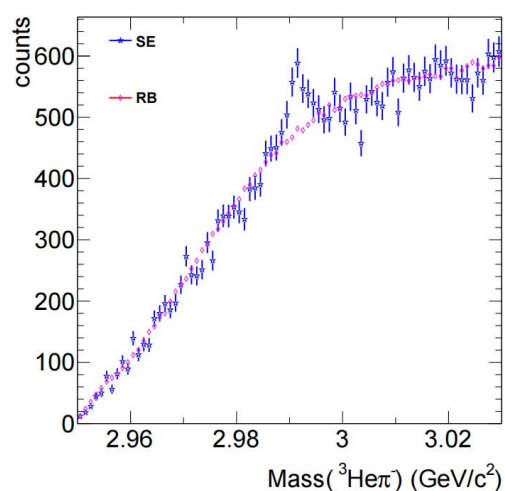


Signal and acceptance

•bin by bin counting

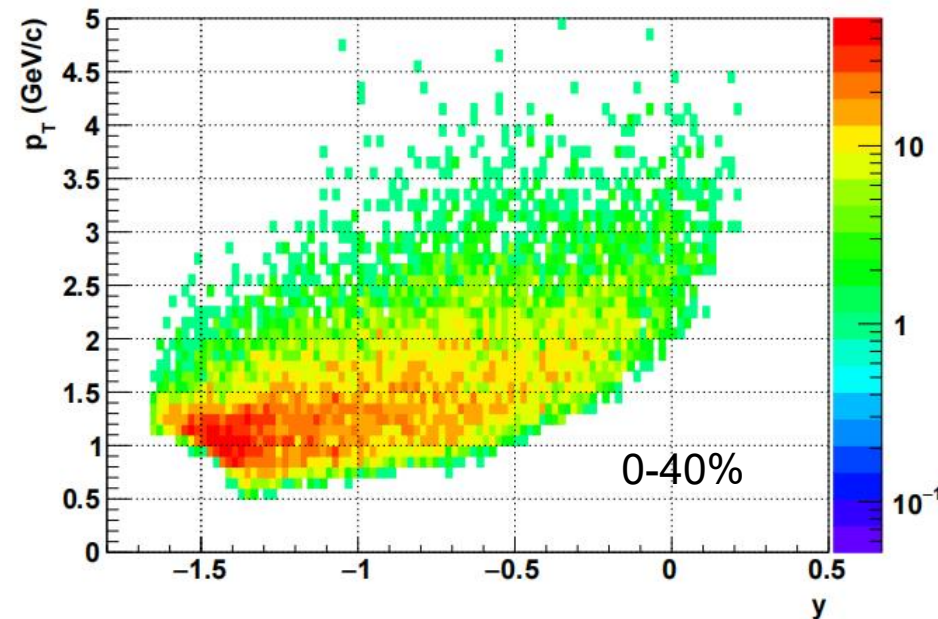
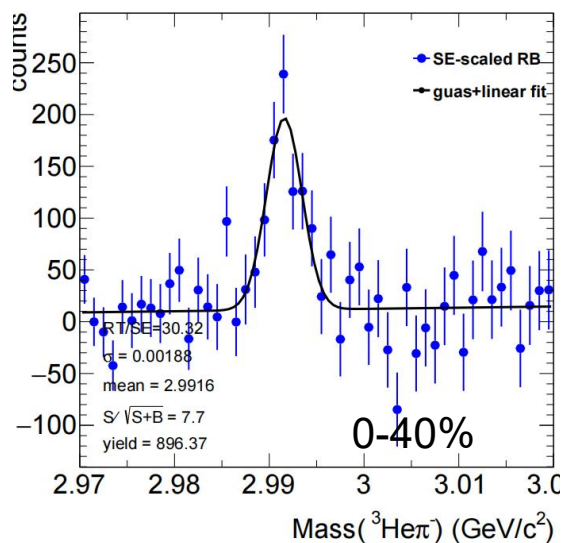
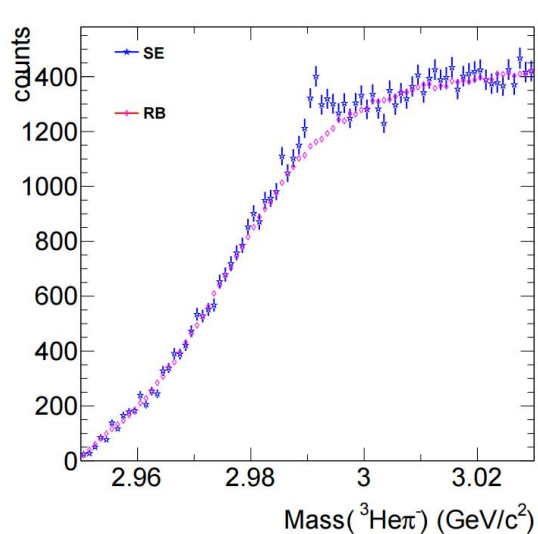
0-10%
 $l > 1, |d| > 6$
 $\chi^2_{\text{topo}} < 5,$
 $\chi^2_{\text{ndf}} < 2.2$
 $\chi^2_{\text{prim}_\pi} > 5$
 $\chi^2_{\text{prim}_\text{he}} > 0$

$p_{T,\pi} > 0.1$



0-40%
 $l > 1, |d| > 6$
 $\chi^2_{\text{topo}} < 5,$
 $\chi^2_{\text{ndf}} < 2.2$
 $\chi^2_{\text{prim}_\pi} > 5$
 $\chi^2_{\text{prim}_\text{he}} > 0$

$p_{T,\pi} > 0.1$

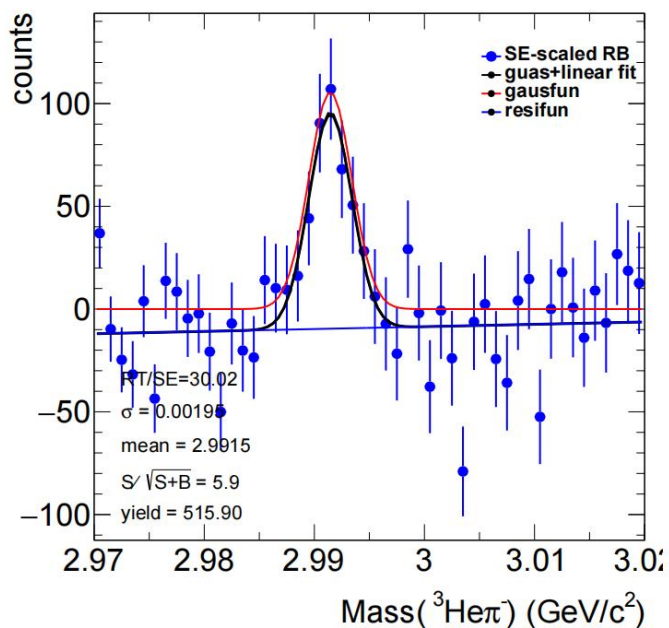


Signal and acceptance

•integral

0-10%
 $l > 1, |d| > 6$
 $\chi^2_{\text{topo}} < 5,$
 $\chi^2_{\text{ndf}} < 2.2$
 $\chi^2_{\text{prim_pi}} > 5$
 $\chi^2_{\text{prim_he}} > 0$

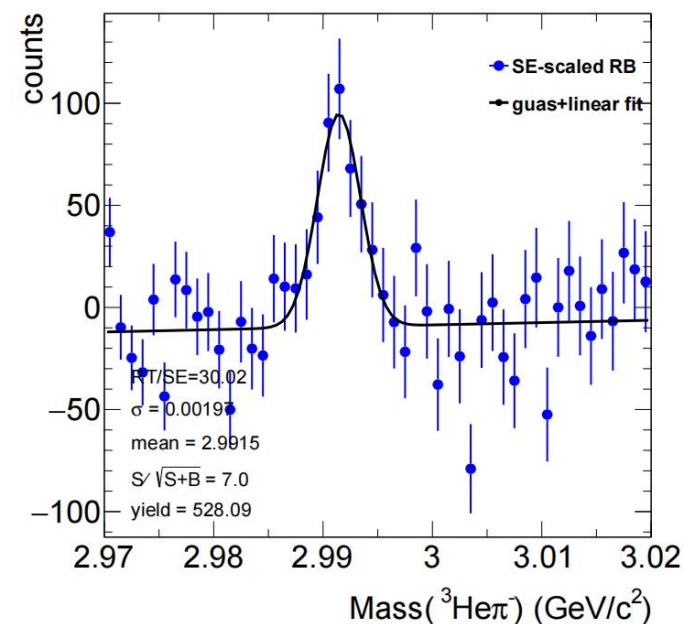
$pt_{\text{pi}} > 0.1$



•bin by bin counting

0-10%
 $l > 1, |d| > 6$
 $\chi^2_{\text{topo}} < 5,$
 $\chi^2_{\text{ndf}} < 2.2$
 $\chi^2_{\text{prim_pi}} > 5$
 $\chi^2_{\text{prim_he}} > 0$

$pt_{\text{pi}} > 0.1$



About integral method

- fit function: $\text{gausn}(0)*[3]+\text{pol1}(4)$
- signal yield :fit function's first parameter
- significance :fit function's first parameter over error of fit function's first parameter

About bin by bin counting method

- fit function: $[1]*\exp(-(x-[0])*(x-[0])/2/[2]/[2]) + [3]+[4]*x$

Signal with different pt and y ranges (three y ranges)

- Cen:0-10%.
- the mass window in each y_pt bin :fitmean-3*fitsigma<particlemass<fitmean+3*fitsigma
- fit function:gaus+line

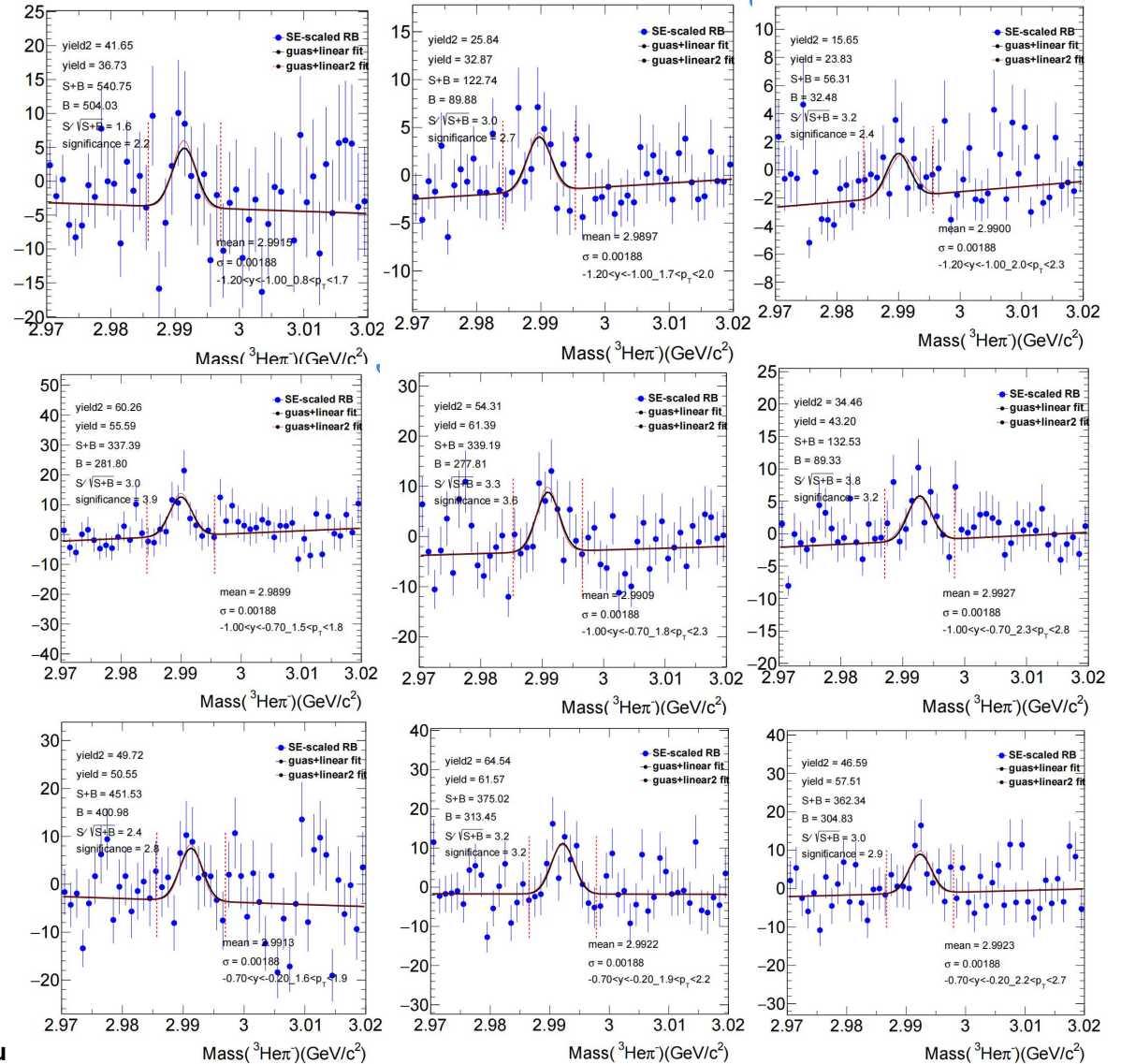
- bin by bin counting(black line)
 - Fix fitmean range(guided by 0-40%) (mean-sigma,mean+sigma)
 - Fix fitsigma(guided by 0-40%)

- integral method(red line)
 - Fix fitmean range(guided by 0-40%) (mean-sigma,mean+sigma)
 - Fix fitsigma(guided by 0-40%) (sigma-0.0002,sigma+0.0002)

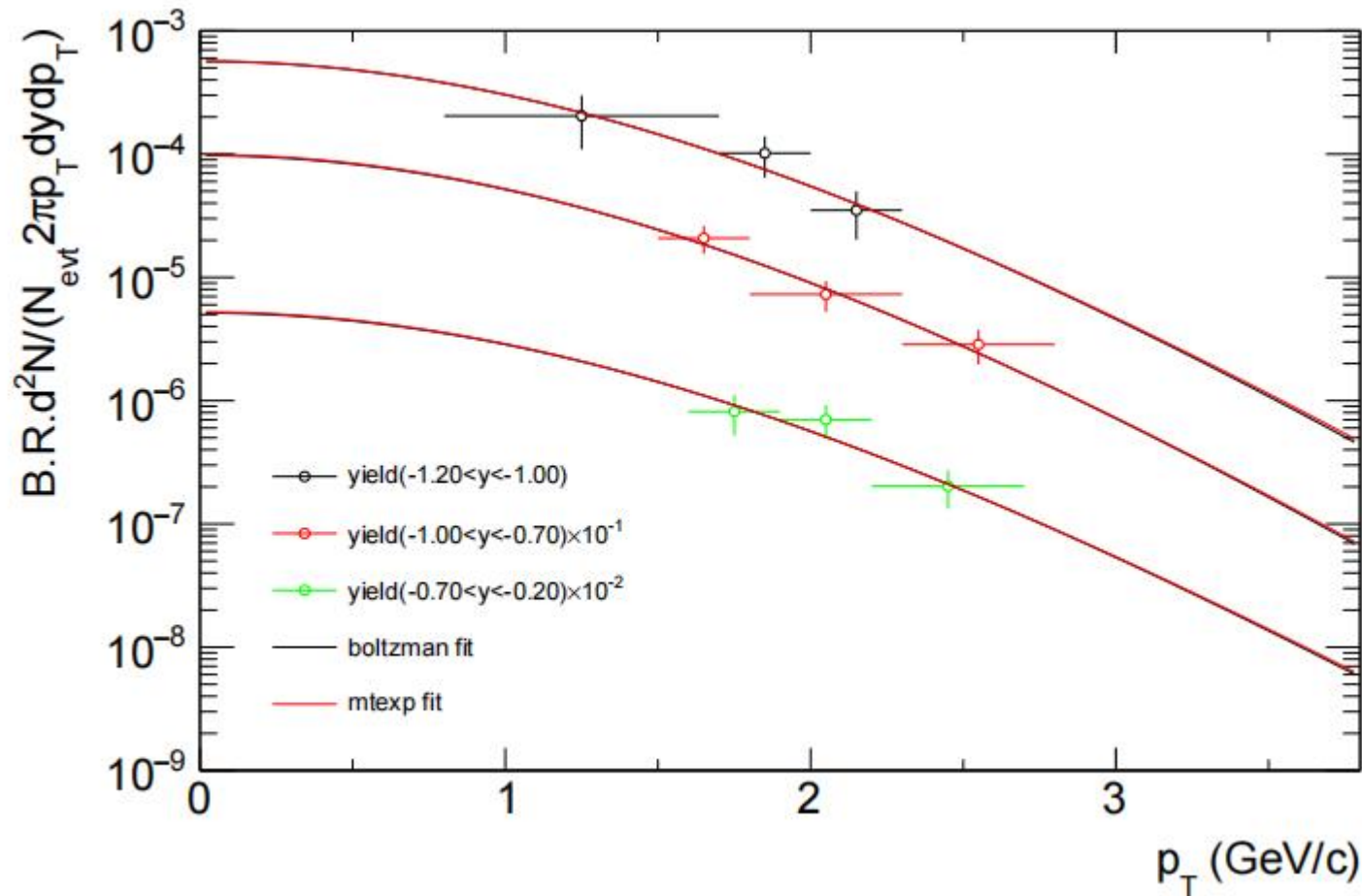
-1.2<y<-1.0

-1.0<y<-0.7

-0.7<y<-0.2



- Cen: 0-10%.
- yield: bin by bin count (• the mass window in each y_{pt} bin is the same as that of no y_{pt} binning)



$$\frac{d^2N}{dp_T dy} = \frac{1}{\text{B.R.}} \times \frac{N_{\text{raw}}}{N_{\text{evt}} \Delta(p_T) \Delta(y)} \times \frac{1}{\epsilon_{\text{TPC}} \times \epsilon_{\text{PID}}}$$

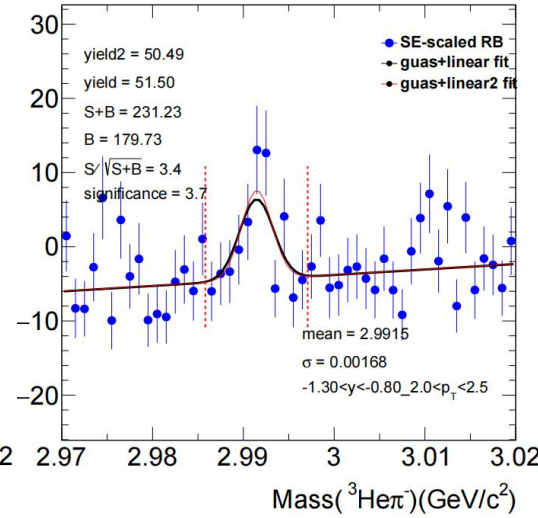
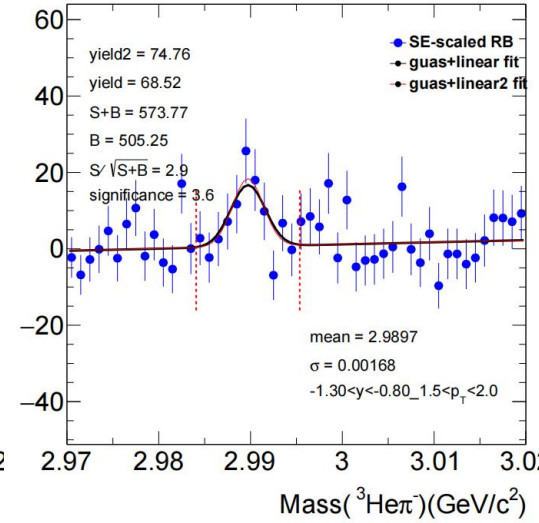
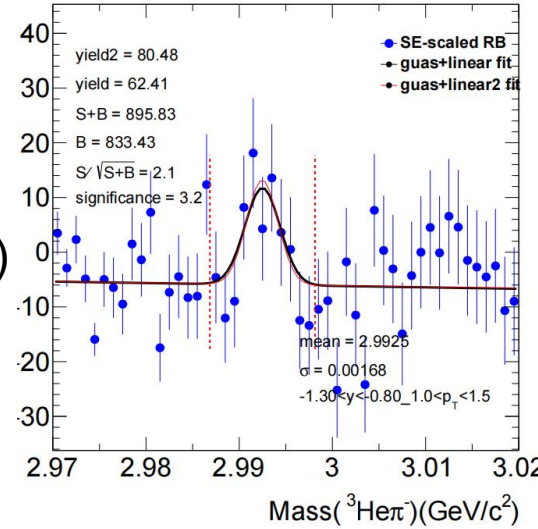
★ spectra:
 N_{raw} : the efficiency corrected signal counts.

★ there are many TH1F corresponding to different y range filled with the calculated values whose X-axis is P_T .

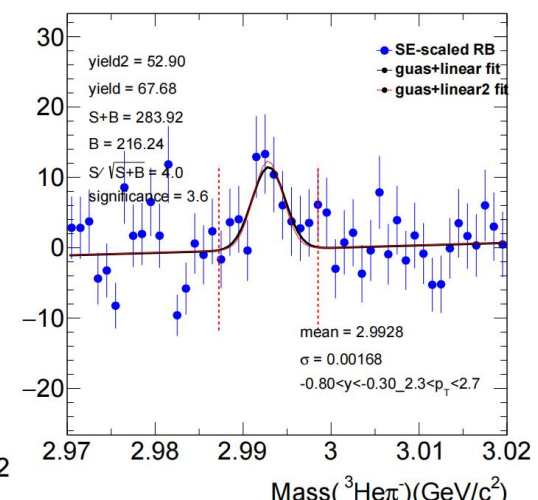
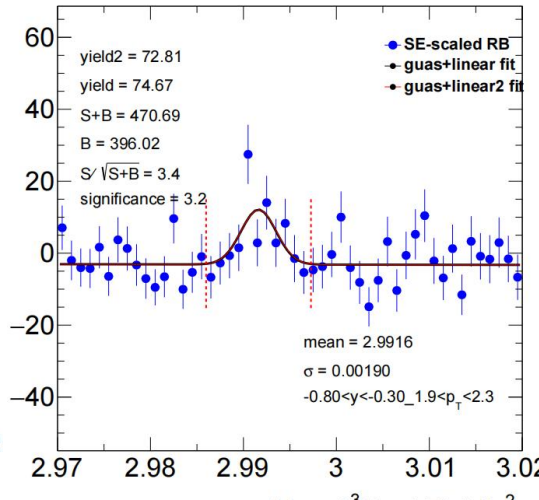
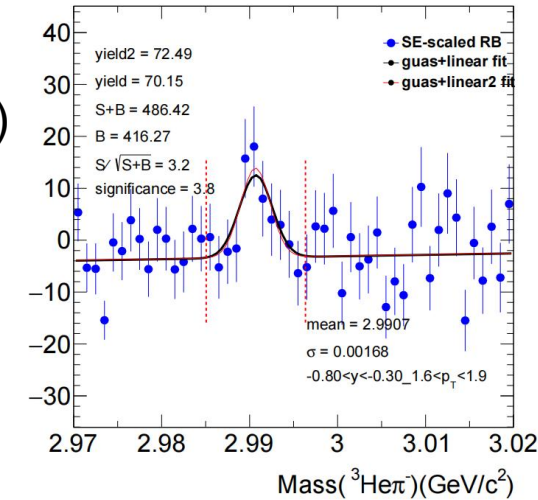
Signal with different pt and y ranges (two y ranges)

- Cen:0-10%.
- the mass window in each y_pt bin : $\text{fitmean}-3*\text{fitsigma}<\text{particlemass}<\text{fitmean}+3*\text{fitsigma}$
- fit function:gaus+line

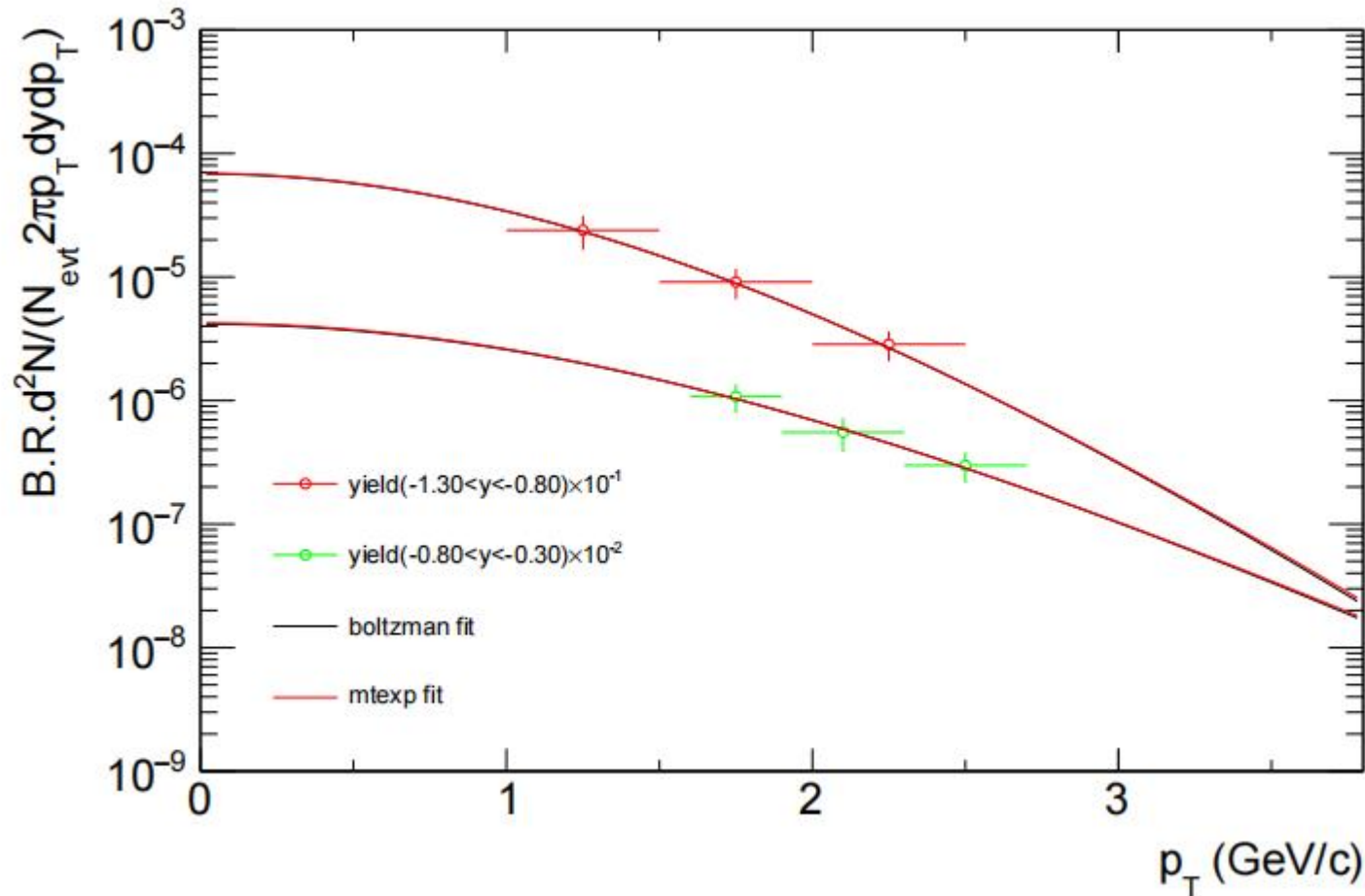
- bin by bin counting(black line)
 - Fix fitmean range(guided by 0-40%) (mean-sigma,mean+sigma)
 - Fix fitsigma(guided by 0-40%)



- integral method(red line)
 - Fix fitmean range(guided by 0-40%) (mean-sigma,mean+sigma)
 - Fix fitsigma(guided by 0-40%) (sigma-0.0002,sigma+0.0002)



- Cen: 0-10%.
- yield: bin by bin count (• the mass window in each y_{pt} bin is the same as that of no y_{pt} binning)



$$\frac{d^2N}{dp_T dy} = \frac{1}{B.R.} \times \frac{N_{raw}}{N_{evt} \Delta(p_T) \Delta(y)} \times \frac{1}{\epsilon_{TPC} \times \epsilon_{PID}}$$

★ spectra:
 N_{raw} : the efficiency corrected signal counts.

★ there are many TH1F corresponding to different y range filled with the calculated values whose X-axis is P_T .